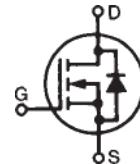


HiPerFET™ Power MOSFETs

IXFR40N50Q2

N-Channel Enhancement Mode
Avalanche Rated, Low Q_g
Low R_g , High dv/dt , Low t_{rr}

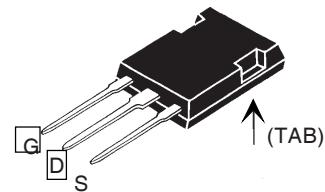
Preliminary Data Sheet



V_{DSS} = 500 V
 I_{D25} = 29 A
 $R_{DS(on)}$ = 0.17 Ω

$t_{rr} \leq 250$ ns

ISOPLUS247 (IXFR)
E153432



G = Gate D = Drain
S = Source TAB = Isolated

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ\text{C}$ to 150°C	500		V
V_{DGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GS} = 1\text{ M}\Omega$	500		V
V_{GS}	Continuous	± 30		V
V_{GSM}	Transient	± 40		V
I_{D25}	$T_c = 25^\circ\text{C}$	29		A
I_{DM}	$T_c = 25^\circ\text{C}$, pulse width limited by T_{JM}	160		A
I_{AR}	$T_c = 25^\circ\text{C}$	40		A
E_{AR}	$T_c = 25^\circ\text{C}$	50		mJ
E_{AS}	$T_c = 25^\circ\text{C}$	2.5		J
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100\text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$, $R_G = 2\Omega$	20		V/ns
P_D	$T_c = 25^\circ\text{C}$	320		W
T_J		-55 ... +150		$^\circ\text{C}$
T_{JM}		150		$^\circ\text{C}$
T_{stg}		-55 ... +150		$^\circ\text{C}$
T_L	1.6 mm (0.063 in) from case for 10 s	300		$^\circ\text{C}$
F_c	Mounting force	22...130/5...30		N/lb.
Weight		5		g

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
V_{DSS}	$V_{GS} = 0\text{ V}$, $I_D = 250\text{ }\mu\text{A}$	500		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 4\text{ mA}$	2.5		5.0 V
I_{GSS}	$V_{GS} = \pm 30\text{ V}_{DC}$, $V_{DS} = 0$		± 200	nA
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0\text{ V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$	25 1	μA mA
$R_{DS(on)}$	$V_{GS} = 10\text{ V}$, $I_D = I_T$ Pulse test, $t \leq 300\text{ }\mu\text{s}$, duty cycle $d \leq 2\%$		0.17	Ω

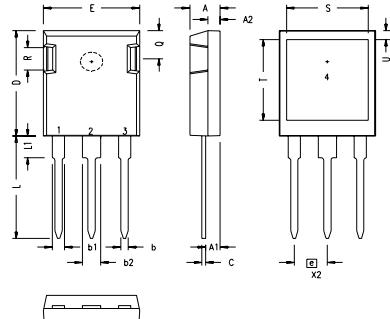
Symbol	Test Conditions	Characteristic Values			
		(T _J = 25°C, unless otherwise specified)	min.	typ.	max.
g_{fs}	V _{DS} = 10 V; I _D = I _T , pulse test	15	28	S	
C _{iss}	V _{GS} = 0 V, V _{DS} = 25 V, f = 1 MHz	4200		pF	
C _{oss}		680		pF	
C _{rss}		170		pF	
t _{d(on)}	V _{GS} = 10 V, V _{DS} = 0.5 • V _{DSS} , I _b = I _T R _G = 2 Ω (External),	17		ns	
t _r		13		ns	
t _{d(off)}		42		ns	
t _f		8		ns	
Q _{g(on)}	V _{GS} = 10 V, V _{DS} = 0.5 • V _{DSS} , I _D = I _T	110		nC	
Q _{gs}		25		nC	
Q _{gd}		50		nC	
R _{thJC}			0.39	K/W	
R _{thCK}		0.15		K/W	

Source-Drain Diode

Characteristic Values
(T_J = 25°C, unless otherwise specified)

Symbol	Test Conditions	min.	typ.	max.
I _s	V _{GS} = 0 V		40	A
I _{SM}	Repetitive; pulse width limited by T _{JM}		160	A
V _{SD}	I _F = I _s , V _{GS} = 0 V, Pulse test, t ≤ 300 μs, duty cycle d ≤ 2 %		1.5	V
t _{rr}	I _F = 25A · di/dt = 100 A/μs, V _R = 100 V	1	250	ns
Q _{RM}		9		μC
I _{RM}				A

Note: Test current I_T = 20A

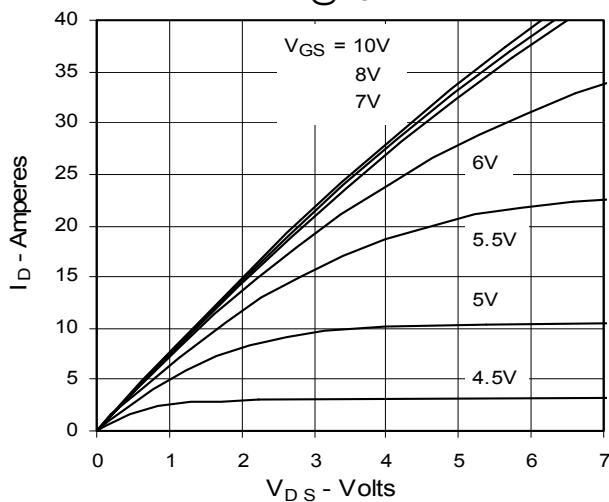
ISOPLUS247 Outline

SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.190	.205	4.83	5.21
A1	.090	.100	2.29	2.54
A2	.075	.085	1.91	2.16
b	.045	.055	1.14	1.40
b1	.075	.084	1.91	2.13
b2	.115	.123	2.92	3.12
C	.024	.031	0.61	0.80
D	.819	.840	20.80	21.34
E	.620	.635	15.75	16.13
e	.215 BSC		5.45 BSC	
L	.780	.800	19.81	20.32
L1	.150	.170	3.81	4.32
Q	.220	.244	5.59	6.20
R	.170	.190	4.32	4.83
S	.520	.540	13.21	13.72
T	.620	.640	15.75	16.26
U	.065	.080	1.65	2.03

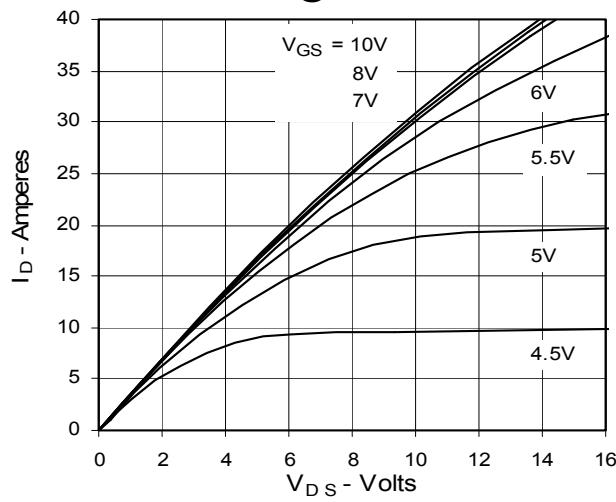
- 1 – GATE
2 – DRAIN (COLLECTOR)
3 – SOURCE (EMITTER)
4 – NO CONNECTION

NOTE: This drawing will meet all dimensions requirement of JEDEC outline TO-247AD except screw hole.

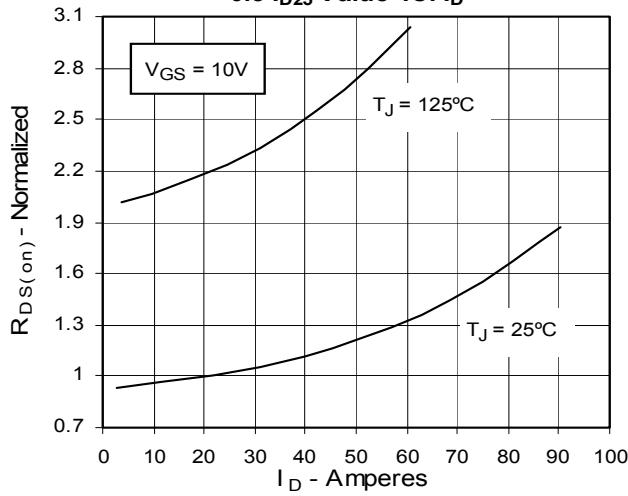
**Fig. 1. Output Characteristics
@ 25°C**



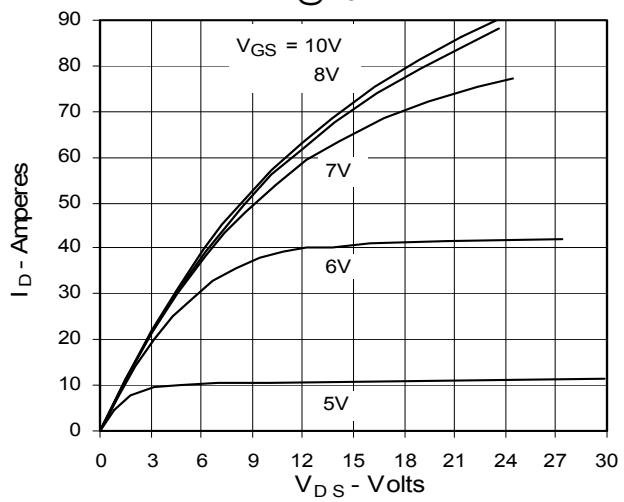
**Fig. 3. Output Characteristics
@ 125°C**



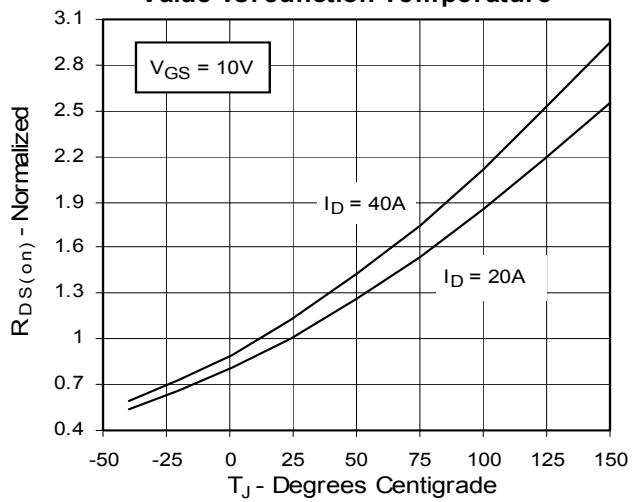
**Fig. 5. $R_{DS(on)}$ Normalized to
0.5 I_{D25} Value vs. I_D**



**Fig. 2. Extended Output Characteristics
@ 25°C**



**Fig. 4. $R_{DS(on)}$ Normalized to 0.5 I_{D25}
Value vs. Junction Temperature**



**Fig. 6. Drain Current vs. Case
Temperature**

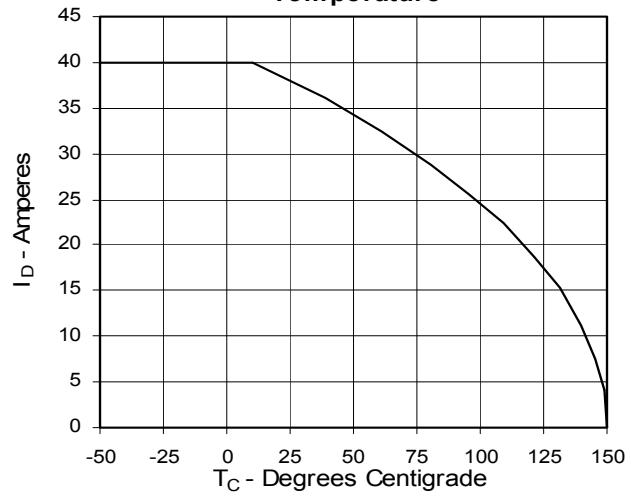
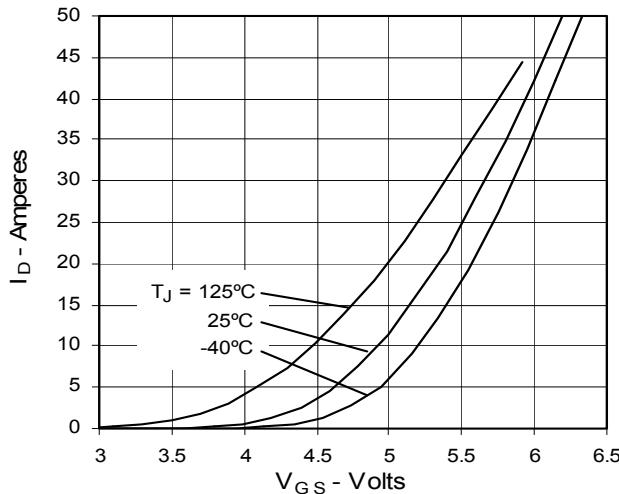
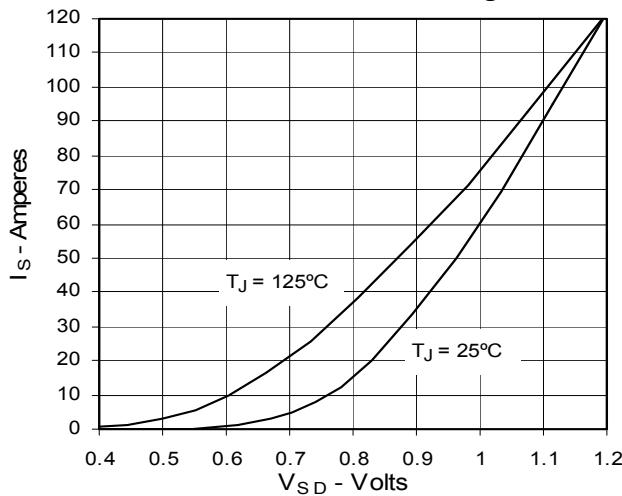
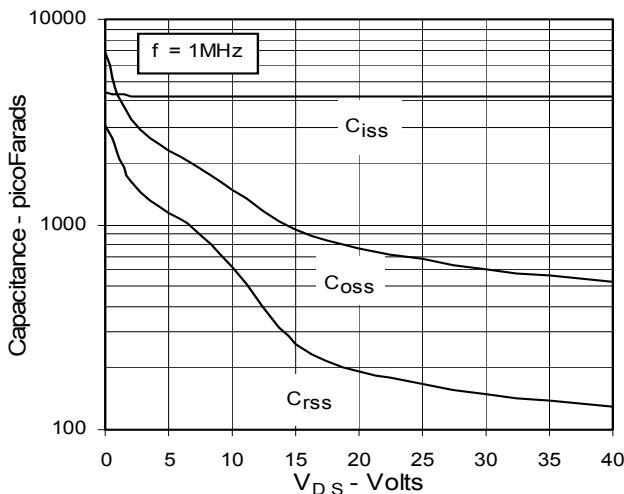
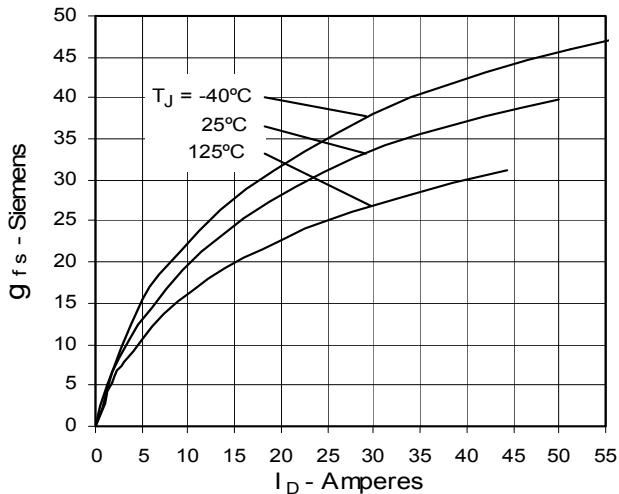
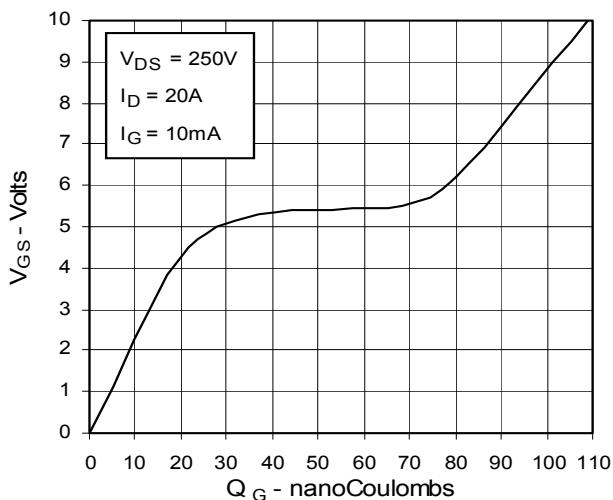
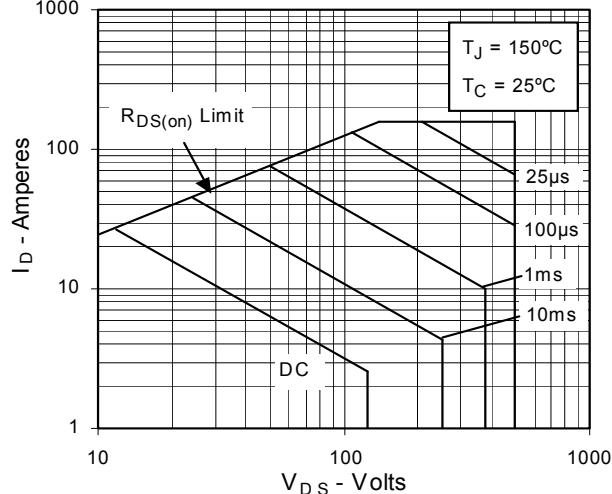


Fig. 7. Input Admittance

Fig. 9. Source Current vs. Source-To-Drain Voltage

Fig. 11. Capacitance

Fig. 8. Transconductance

Fig. 10. Gate Charge

Fig. 12. Forward-Bias Safe Operating Area


IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following U.S. patents:

4,850,072	4,931,844	5,034,796	5,063,307	5,237,481	5,381,025	6,404,065B1	6,162,665	6,534,343	6,583,505
4,835,592	4,881,106	5,017,508	5,049,961	5,187,117	5,486,715	6,306,728B1	6,259,123B1	6,306,728B1	6,683,344

Fig. 13. Maximum Transient Thermal Resistance